High resolution hard x-ray spectroscopy of femtosecond laser-produced plasmas with a CZT detector

L. M. Chen, a) P. Forget, R. Toth, and J. C. Kieffer
INRS--Energie, Materiaux, Telecommunication, Varennes, Quebec J3X 1S2, Canada

A. Krol and C. C. Chamberlain
Upstate Medical University, State University of New York (SUNY), Syracuse, New York 13210

B. X. Hou, J. Nees, and G. Mourou
CUOS, University of Michigan, Ann Arbor, Michigan 48109

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We present measurement of characteristic $K\alpha$ emission from Mo, Ag, and La targets irradiated by a 60 fs, 600 mJ, 10 Hz Ti:sapphire laser pulse at $10^{17}$–$10^{19}$ W/cm$^2$. These x-ray emissions can potentially be used in applications from laser-based hard x-ray sources to x-ray mammography so detailed knowledge of the spectra is required to assess imaging of the figure of merit. We show here that high resolving hard x-ray spectroscopy can be achieved, with resolving powers $(E/\Delta E)$ of 60 at 18 keV, with cadmium–zinc–telluride detection system. The $K\alpha$ conversion efficiency from the laser light to the $K\alpha$ photon was optimized thanks to this diagnostic and values as high as $2 \times 10^{-5}$ were obtained. © 2003 American Institute of Physics. [DOI: 10.1063/1.1628824]

I. INTRODUCTION

Hard x-ray emission from femtosecond laser-produced plasmas has been extensively studied in the past few years.1–15 These hard x-ray sources have a number of interesting applications in the dynamic probing of matter and in medical imaging.16–23 However further development of both sources and detection systems is needed for practical application. Quantitative assessment of the image quality obtained with a laser-based x-ray source can be made by modeling the imaging process and by evaluating the figure of merit (FOM), which is defined as the quotient of the signal-to-noise ratio and the square root of the integral dose, $23,24$ for various imaged objects and x-ray source characteristics. Thus detailed knowledge of the x-ray source (spectrum, source size, and x-ray yield) as a function of the laser and target parameters is essential for optimization of the imaging parameters.

In some previous studies the hard x-ray spectrum, with photons energies above 10 keV, has been measured by a photomultiplier coupled to NaI scintillators using the Ross filter technique.8 The resolution of this technique is rather limited because of the low number of elements. Combinations of ionization chambers and scintillators coupled to a charge coupled device (CCD) with different absorption filters have also been used for hard x-ray diagnostics and have better resolving power $E/\Delta E$.25 Since detailed spectra are crucial as input parameters for FOM calculations, high-resolution spectroscopy is needed for a quantitative comparison between measured and calculated FOMs. Here we present measurements with a high resolving cadmium–zinc–telluride (CZT) detection system. This single-photon-counting CZT detector can be used to measure hard x-ray spectra with resolving powers $(E/\Delta E)$ of 60 at 18 keV and 86 at 60 keV.

II. EXPERIMENTAL APPARATUS

Experiments were carried out with the INRS 10 TW Ti:sapphire femtosecond system. This laser delivers 60 fs pulses at 800 nm with 600 mJ energy, at 10 Hz repetition rate. The $p$-polarized beam is focused with an off-axis parabola at an incidence angle of 56° into a focal spot of 10 $\mu$m diameter, giving rise to maximum intensity of $5 \times 10^{19}$ W/cm$^2$. The pulse contrast at the fundamental frequency was measured with a third-order autocorrelator and was around $1 \times 10^{-5}$ and $1 \times 10^{-4}$ at 100 ps and a few picoseconds before the main pulse, respectively. The target was rotated to ensure that each laser shot was incident on a fresh target surface. Thick flat Mo, Ag, and La targets were used in the experiments.

High-resolution line spectra were measured with a CZT detector26 coupled to a charge sensitive preamplifier (Amptek model A250) and to a multichannel analyzer (MCA) (micro-ACE from Ortec with 2048 channels and MAESTRO-32 MCA emulator software). The thermoelectrically cooled Cd$_{0.9}$Zn$_{0.1}$Te detector (model XR-100T-CZT) has a light and vacuum tight 250 $\mu$m beryllium window in front to enable hard x-ray detection. The CZT detection efficiency remains constant in the energy range of 8–100 keV. The MCA has zero adjustment to reduce noise and each channel corresponds to 61 eV. This system includes rise time discrimination (RTD) that can be used to internally gate the shaped pulses thus allowing pulses corresponding to real x-ray events to be sent to the MCA for analysis. With RTD, partial charge collection can be expelled thus increasing the energy resolution. The detection system was calibrated with two radiation sources, $^{133}$Ba (at 14 and 60 keV) and $^{241}$Am

a)Electronic mail: lmcchen18@yahoo.com

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The temperature in keV and laser intensity $I$ was around 50 for a 20 keV x-ray source size, measured with the knife-edge technique, was around 50 for a 20 keV x-ray source size, measured with the knife-edge technique.

The temperature, $T$, has the following form: $K T h \alpha = \text{constant}$, represented by a Maxwellian distribution of Ross filters.

The hard x-ray spectra were measured between 10 and 100 keV for various intensities and laser pulse durations. All the spectra exhibited a continuum bremsstrahlung emission and individual characteristic K-line emission, as shown in Fig. 2(a) (measurement with the CZT detector without any filter) for a Mo target irradiated at $2 \times 10^{17}$ W/cm$^2$. Assuming that the hot electrons generating the x-ray spectrum can be represented by a Maxwellian distribution $[f(E) \propto e^{-E/KT_h}]$, the slope of the continuum spectrum gives the hot electron temperature, $K T_h$. The scaling law deduced from the spectra recorded at various intensities ranging from $1 \times 10^{17}$ to $5 \times 10^{18}$ W/cm$^2$ with pulse durations between 60 and 400 fs has the following form: $K T_h = 6 \times 10^{-5}(I)^{0.33}$, where $K T_h$ is the temperature in keV and laser intensity $I$ is in W/cm$^2$. The 20 keV x-ray source size, measured with the knife-edge technique, was around 50 μm, indicating the presence of lateral plasma transport, as already observed previously by us and in some other experiments under different conditions. At these high laser intensities, the pedestal plays a very important role and affects the generation, dynamics, and trajectories of the hot electrons.

Figure 2(b) shows a high-resolution spectrum of Mo K lines measured with a 50 μm Mo filter placed in front of the detector. This spectrum was obtained with a 200 fs pulse incident at $2 \times 10^{17}$ W/cm$^2$ on thick Mo targets. Under these conditions, the bremsstrahlung emission around the K lines is sufficiently reduced to allow characteristic emission to dominate the spectra. The resolving power is around 70 and the FWHM of the Mo Kα line is around 360 eV. Thus, the two $K \alpha_1$ and $K \alpha_2$ lines, which are separated by 100 eV, are not resolved here. However, we do clearly see the $K \beta_1$ (19.61 keV) and $K \beta_2$ (19.96 keV) line emission.

This spectrum can be compared to the spectrum obtained under exactly the same experimental conditions on the same shots with a National Institute for Standards and Technology (NIST) bent crystal spectrometer. Figure 3 shows the characteristic line emission obtained with resolving power for Mo Kα emission of about 80, which is just slightly higher than the CZT detector’s resolution. Compared with the CZT detector, this crystal spectrometer has slightly better resolution but a more limited range of detection (12–60 keV).
Furthermore, absolute calibration and secondary data reconstruction are needed to get a quantitative evaluation of the emission yield. Compared to the CZT, the crystal system has a nonlinear response in the photon energy range of interest here and that is why we cannot observe the continuum x-ray emission or monitor the hot electron temperature.

Figure 4 shows a spectrum obtained with a La target irradiated with 60 fs pulses at $2 \times 10^{18}$ W/cm$^2$. The CZT detector is in this case used to monitor the hot electron temperature.

The conversion efficiency $\eta$ from laser light into $K\alpha$ emission (emitted in $2\pi$ srd) deduced from the high resolution CZT measurements with an Ag target was compared to the one inferred from photomultipliers coupled to a pair of Ross filters composed of a 100 $\mu$m Sm filter in front of the CZT system.

Figure 5 presents the variation of $\eta$ as a function of the laser intensity for both measurement techniques. We observe good agreement between the two methods and we see that, in this experiment, $\eta$ increases with the laser intensity and then saturates at around $2 \times 10^{-5}$ for laser intensities above $2 \times 10^{18}$ W/cm$^2$, resulting in average x-ray power of 0.1 mW in one line emission at 25 keV (for laser average power of 6 W). At this intensity the total conversion efficiency in x rays with photon energies above 10 keV is $4 \times 10^{-4}$.

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